# **FQP24N08**

## **80V N-Channel MOSFET**

### **General Description**

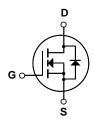
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as automotive, high efficiency switching for DC/DC converters, and DC motor control.

#### **Features**

- 24A, 80V,  $R_{DS(on)} = 0.06\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 19 nC)
- Low Crss (typical 50 pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- 175°C maximum junction temperature rating





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQP24N08	Units
V <sub>DSS</sub>	Drain-Source Voltage		80	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°	C)	24	Α
	- Continuous (T <sub>C</sub> = 100	)°C)	17	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	96	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 25	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	230	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	24	А
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	7.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.5	V/ns
$P_D$	Power Dissipation (T <sub>C</sub> = 25°C)		75	W
	- Derate above 25°C		0.5	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

## **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.0	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

1 10 100 100 4.0 048 0.06 12	V V/°C μA μA nA nA nA S
.08 1 10 100100 4.0 048 0.06 12	V/°C μA μA nA nA
1 10 100 100 4.0 048 0.06 12	μΑ μΑ nA nA
10 100 100 4.0 0.06 12 80 750	μA nA nA Ω
100 100 4.0 048 0.06 12	nA nA V Ω S
100 4.0 048 0.06 12 80 750	nA V Ω S
4.0 048 0.06 12	V Ω S
048 0.06 12 80 750	Ω
048 0.06 12 80 750	Ω
12 80 750	S
80 750	
	pF
10 270 50 65	pF pF
00 03	pi
10 30	ns
05 220	ns
	ns
	ns
	nC
	nC
	nC
24	A
	V
1.5	
32	ns
	30 70 35 80 19 25 1.2 0.6

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 0.55mH, I<sub>AS</sub> = 24A, V<sub>DD</sub> = 25V, R<sub>G</sub> = 25  $\Omega$ , Starting T<sub>J</sub> =  $25^{\circ}\text{C}$  3. I<sub>SD</sub>  $\leq 24\text{A}$ , di/dt  $\leq 300\text{A/µs}$ , V<sub>DD</sub>  $\leq \text{BV}_{DSS}$ , Starting T<sub>J</sub> =  $25^{\circ}\text{C}$  4. Pulse Test : Pulse width  $\leq 300\text{µs}$ , Duty cycle  $\leq 2\%$  5. Essentially independent of operating temperature

# **Typical Characteristics**

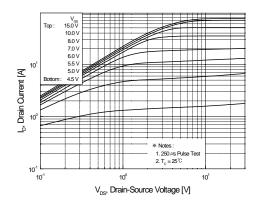


Figure 1. On-Region Characteristics

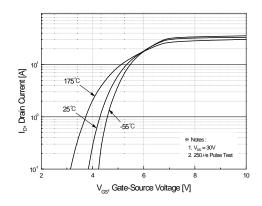


Figure 2. Transfer Characteristics

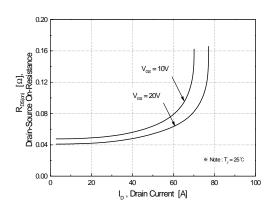


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

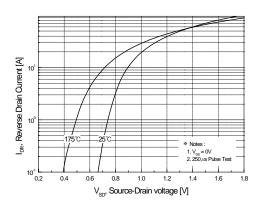


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

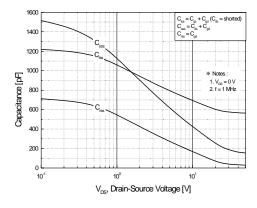


Figure 5. Capacitance Characteristics

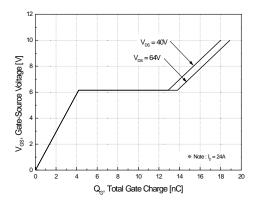
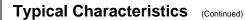
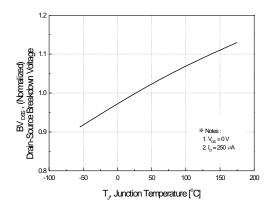


Figure 6. Gate Charge Characteristics

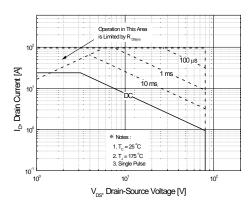




30 25 (Noting Fig. 20) 1.5 (No

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



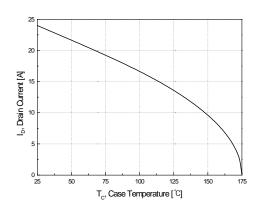


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

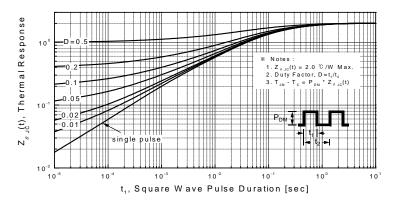
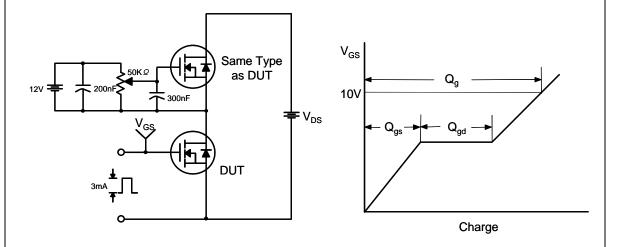


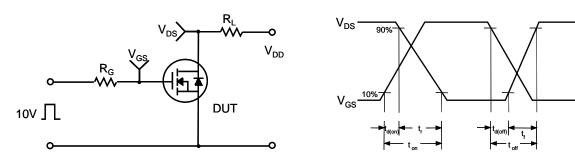
Figure 11. Transient Thermal Response Curve

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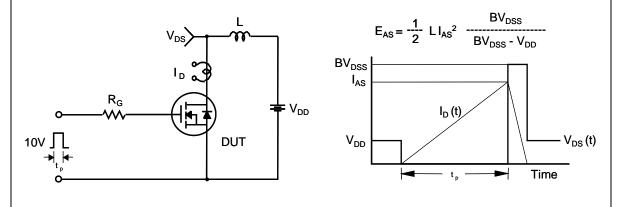
## **Gate Charge Test Circuit & Waveform**



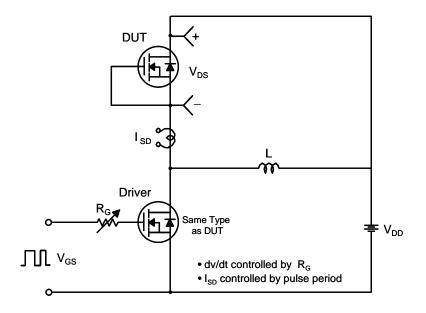
## **Resistive Switching Test Circuit & Waveforms**

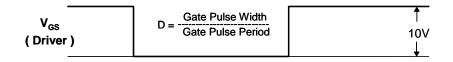


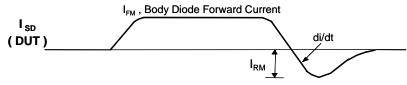
## **Unclamped Inductive Switching Test Circuit & Waveforms**



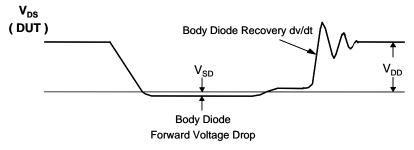
## Peak Diode Recovery dv/dt Test Circuit & Waveforms

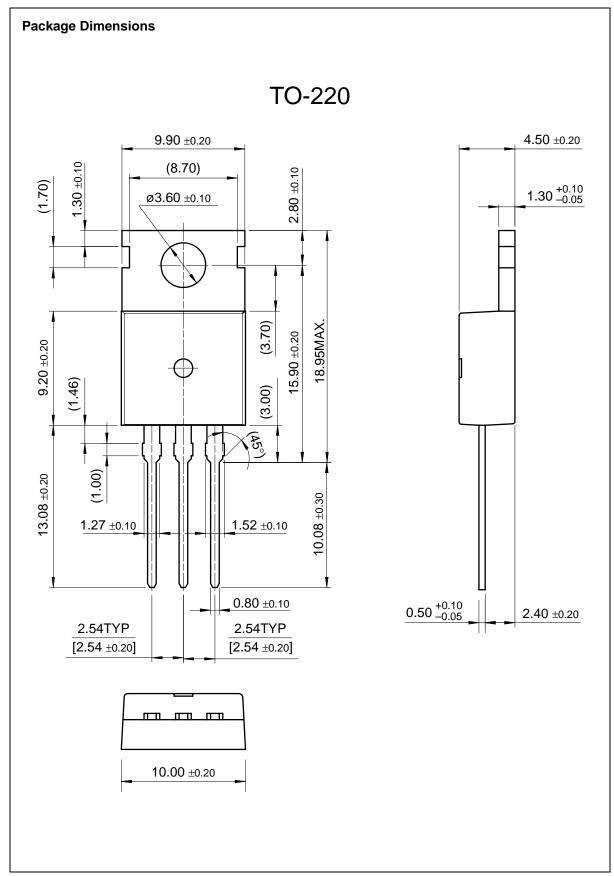






Body Diode Reverse Current





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